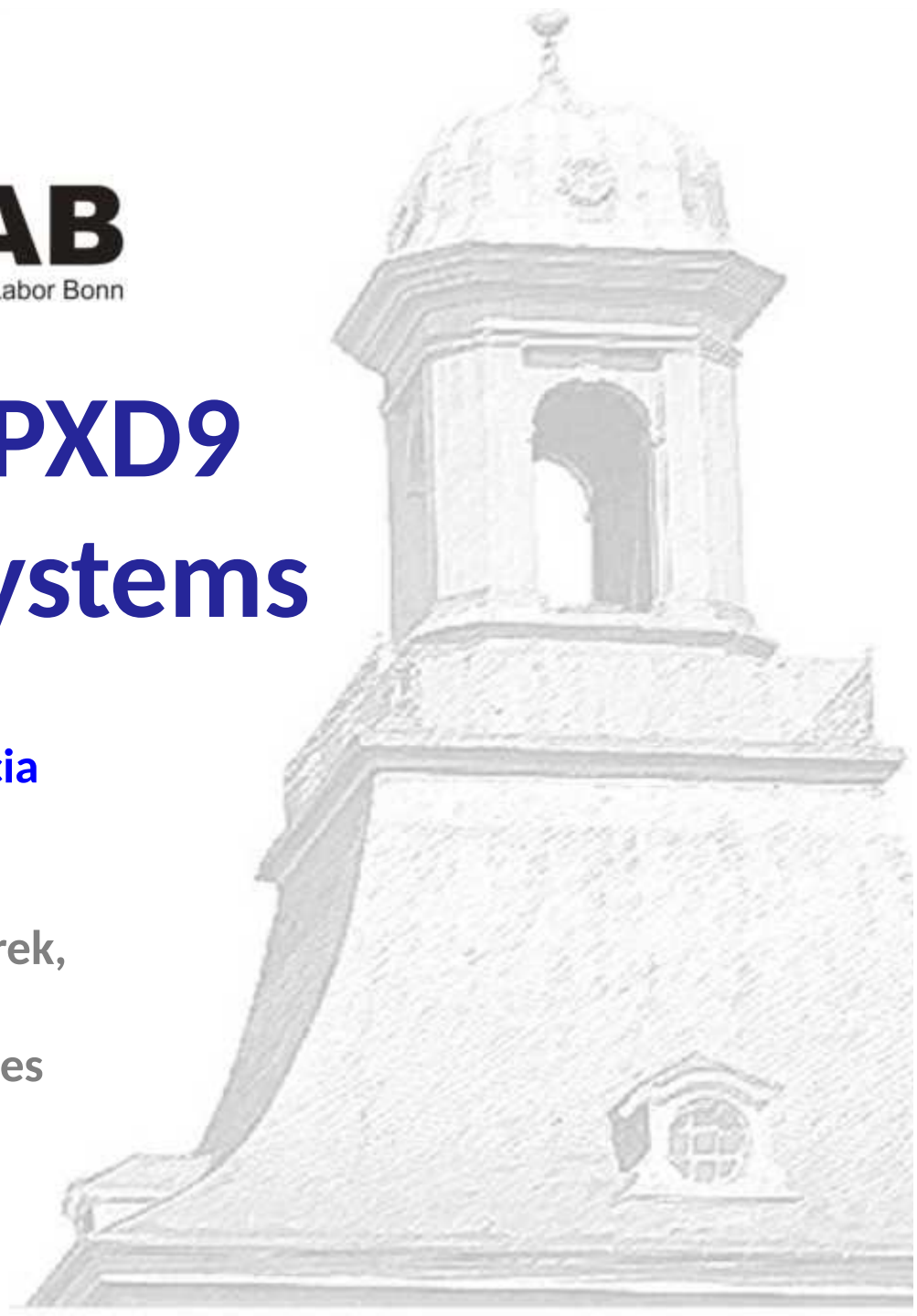


DHPT1.0/1.1 and PXD9 Tests on Hybrid 5 Systems

9th Belle II VXD workshop
13th-15th January 2016, IFIC Valencia

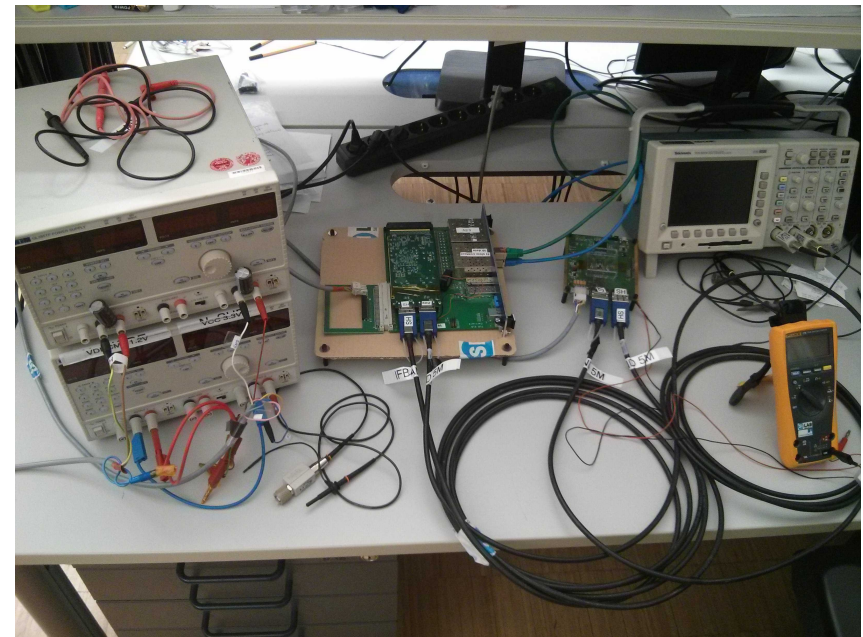
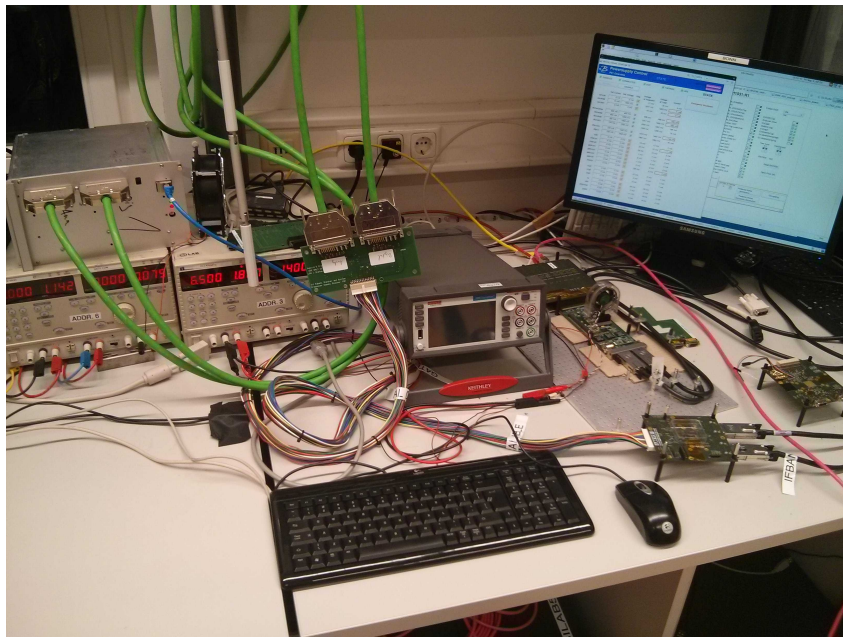
J. Dingfelder, L. Germic, T. Hemperek,
C. Hönig, H Krüger, F. Lütticke,
C. Marinas, B. Paschen, N. Wermes

University of Bonn

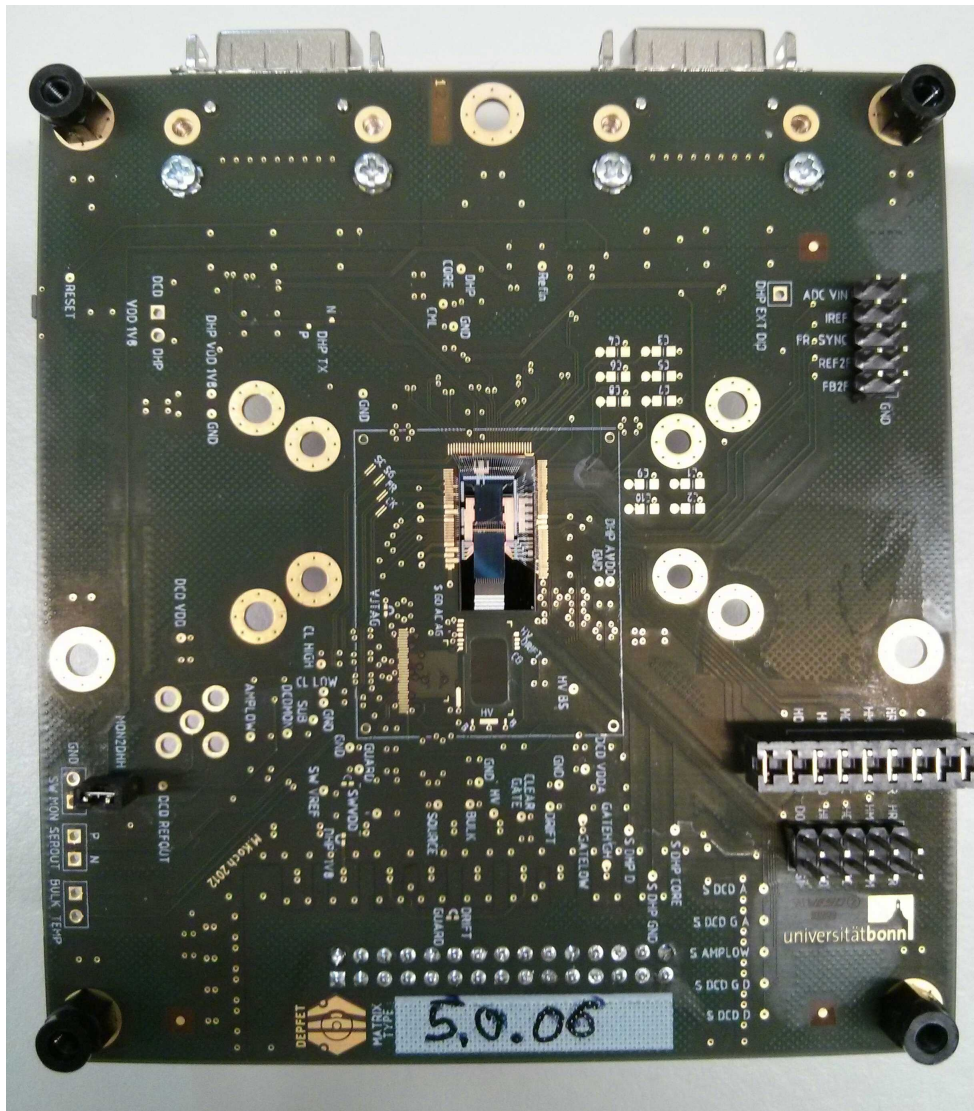


- Setups in Bonn
- Hybrid 5 test system optimization
- PXD9 small matrix laboratory test
- DHPT1.1 ↔ DCD communication

- Setup 1:
DHH and LMU-PS
for Hybrid 6 testing
- Setup 2:
DHH and LMU-PS
for Hybrid 5 testing
- Setup 3:
DHH
for debug cart (bonded DHP + FPGA)
or needle cart (contacted DHP + FPGA)



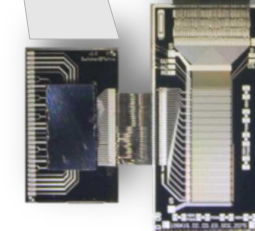
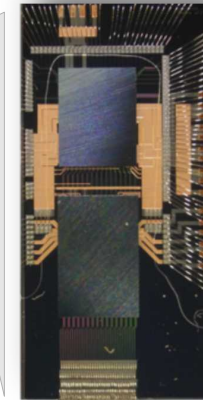
- Additional DHH for dedicated Switcher/Gated Mode tests requested



[Hybrid 5.0.06]

wirebond
adapters

switcher



DHP

(Data Handling Processor)

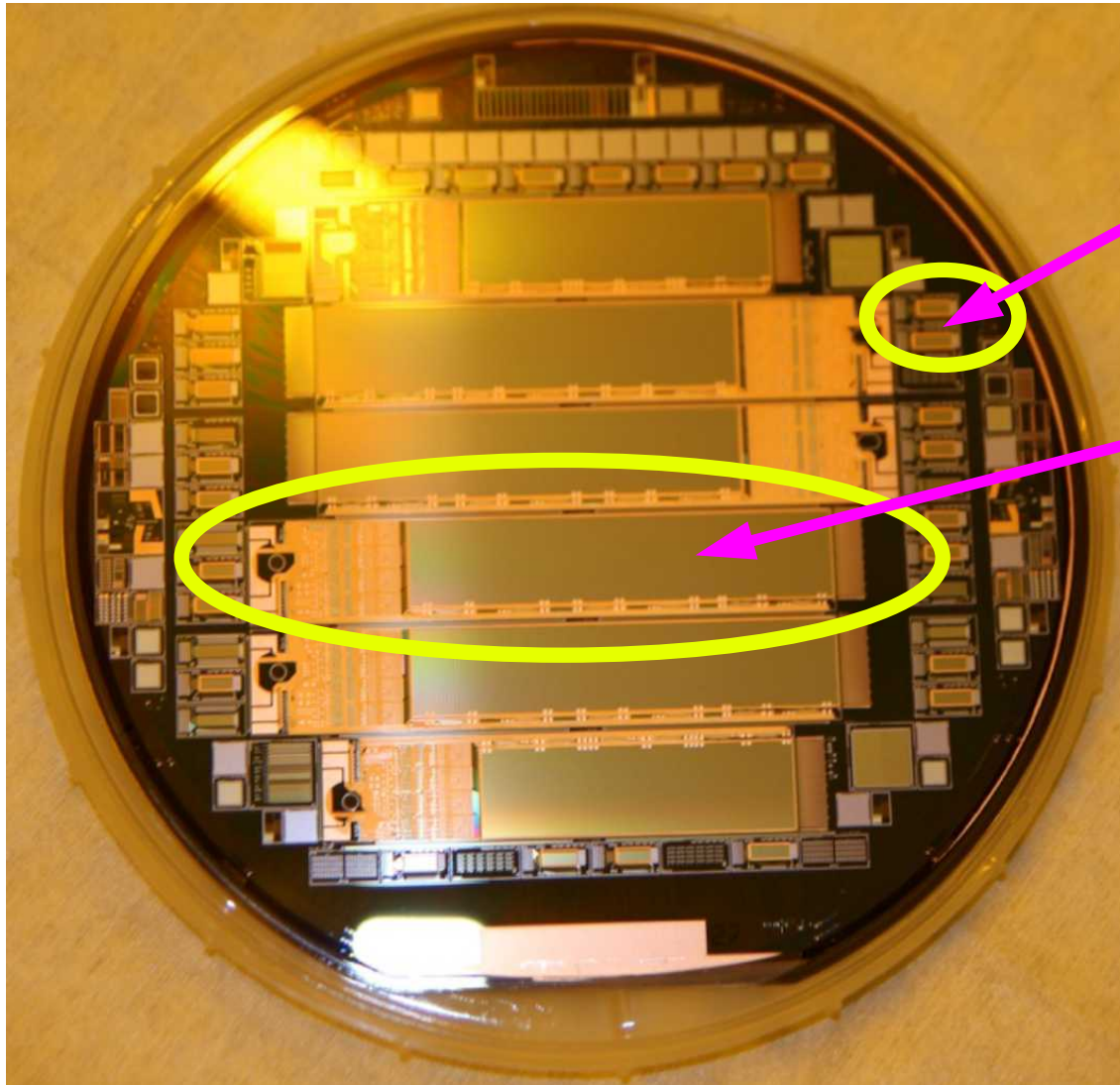
DCD

(Drain Current
Digitizer)

small matrix

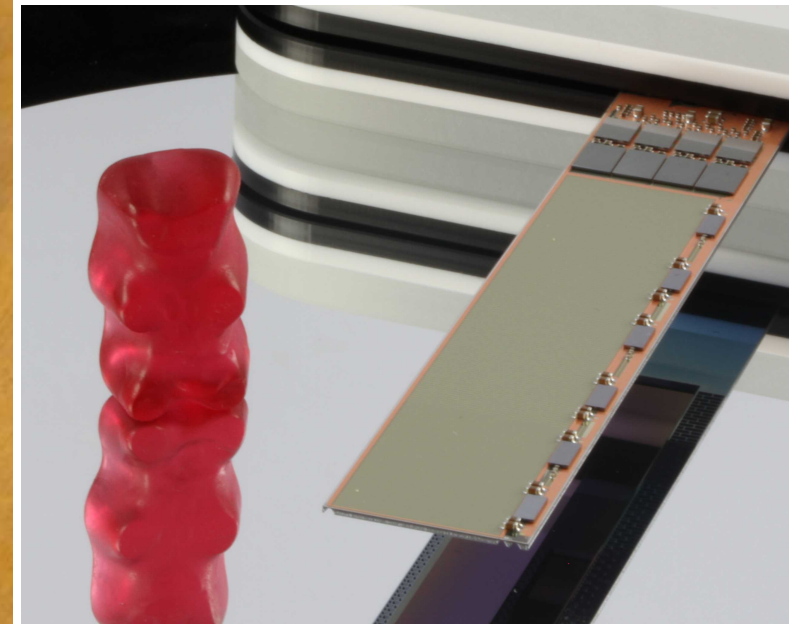
(64x32 DEPFET pixels)
(16 gates, 128 drain lines)

- Can be equipped with 1 DHP, 1 DCD, 1 Switcher and 1 small matrix
- ASICs are bump-bonded to wirebond adapters
- Connection via 2 Infiniband cables and one Samtec multipole power connection



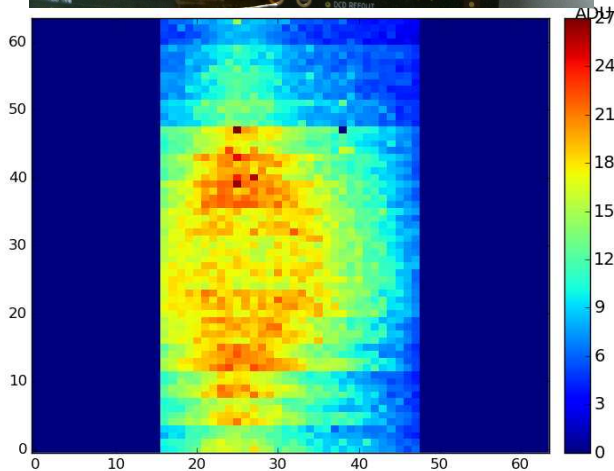
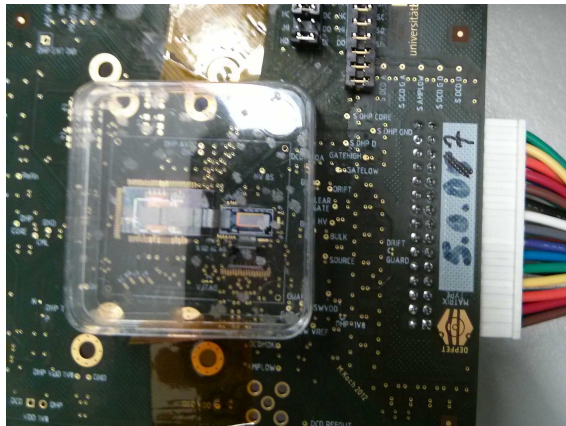
Small matrices
(80 x 32 pixels)
(16 gates, 128 drainlines)

**Full modules with
Large matrices**
(768 x 250 pixels)
(192 gates, 1000 drainlines)



Fully equipped Hybrid 5.0.07 (and 5.0.06)

- Two Hybrid 5 boards assembled with by then most recent ASICs (DHPT1.0, DCDpp, SwitcherB) and small PXD9 matrix in October 2015
- Test beam preparation campaign in Bonn with GOE and HLL

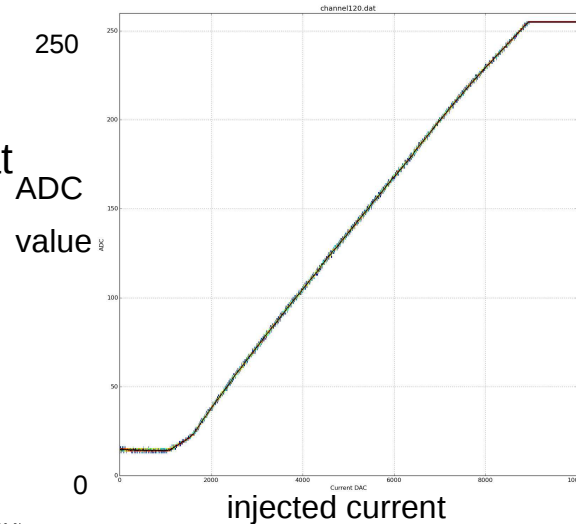


Laser pointer on PXD9 matrix
(slightly wrong mapping)



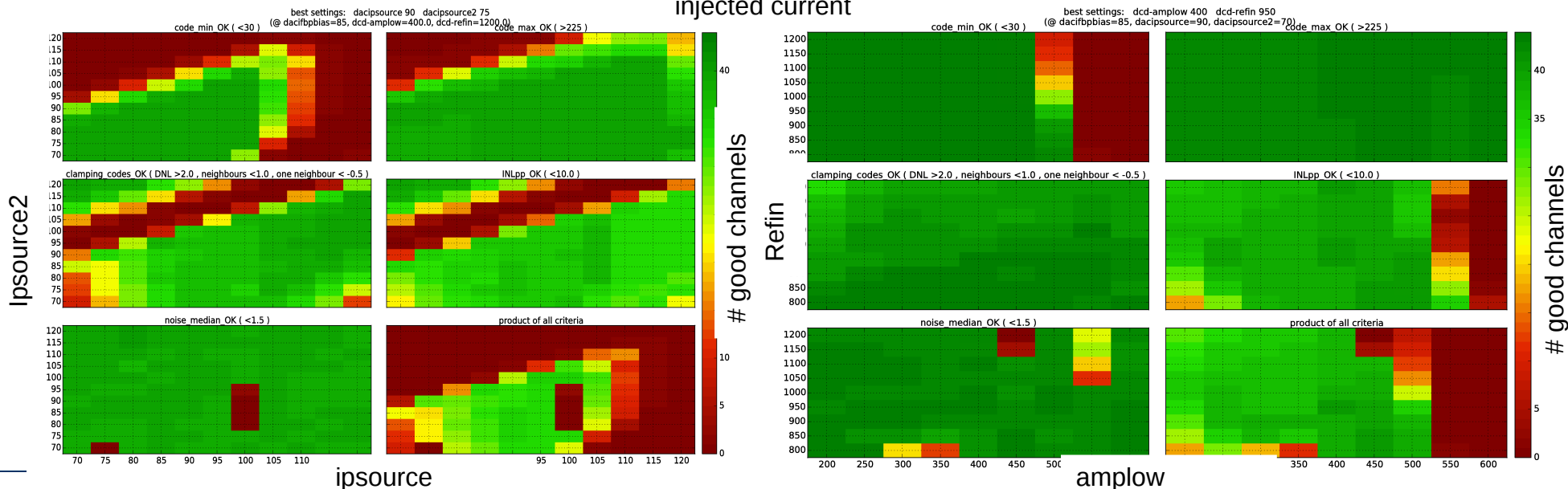
Two full Hybrid 5 setups operated in parallel on one desk

- ADC parameters of DCD optimized
256 8 bit ADCs per DCD
- Scans over two parameters at a time for a representative number of channels
- Automated analysis:



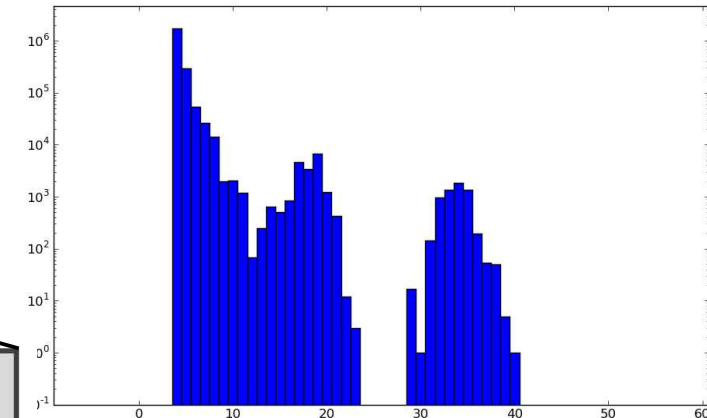
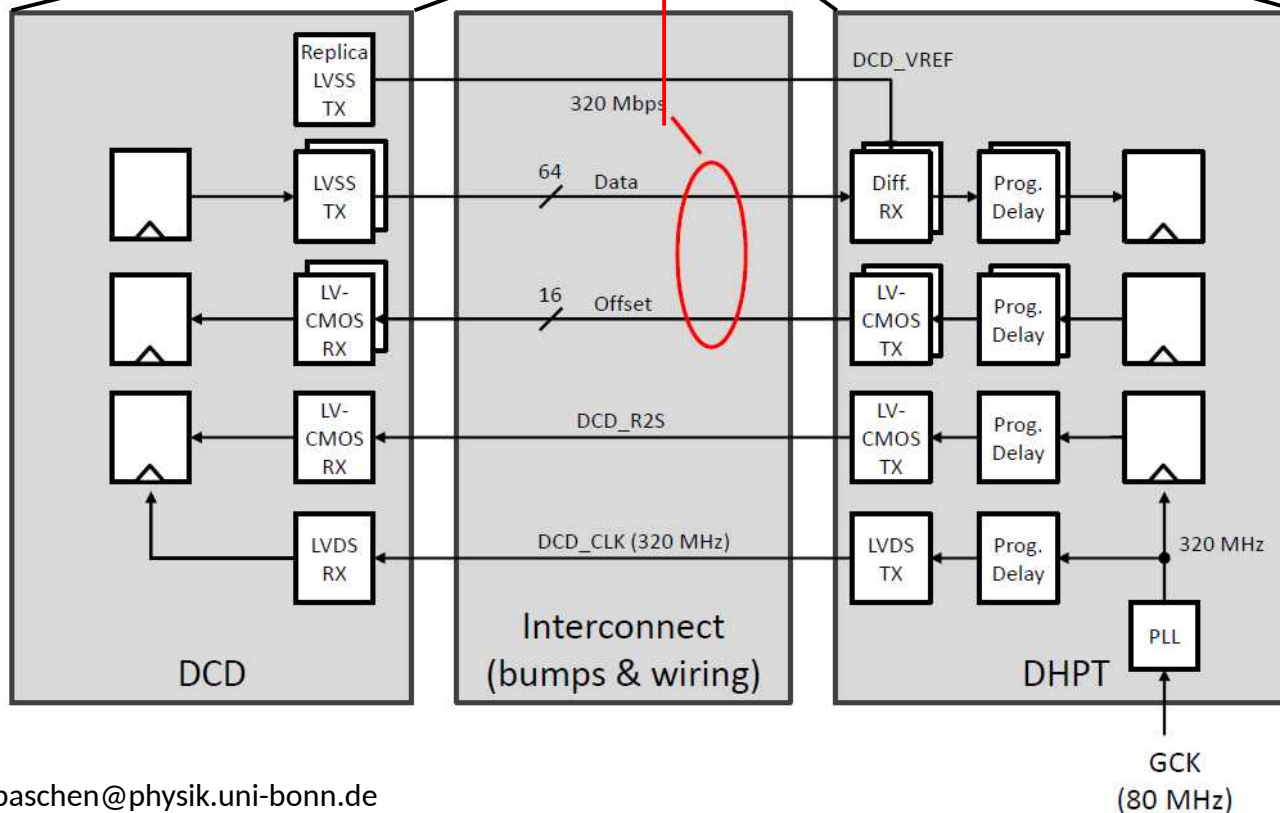
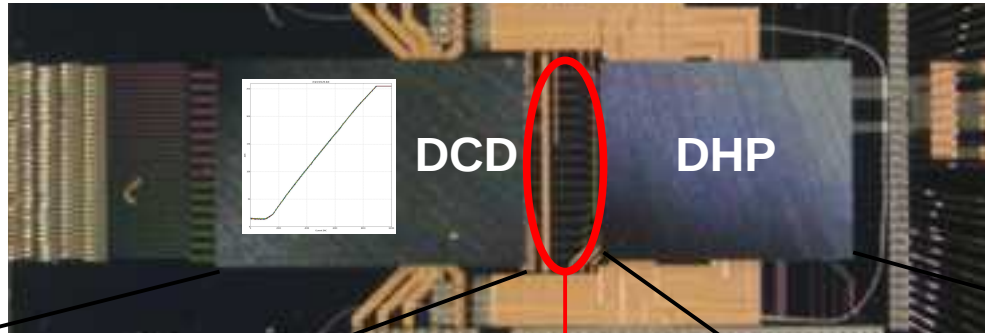
Main DCD parameters:

- Amplow (PS voltage)
- Refin (PS voltage)
- Ipsource (DAC)
- Ipsource2 (DAC)
- lfbpbias (DAC)



Optimization of DCD ↔ DHP communication

- Transmission of ADC values disturbed by digital errors (see previous talk by Benjamin)



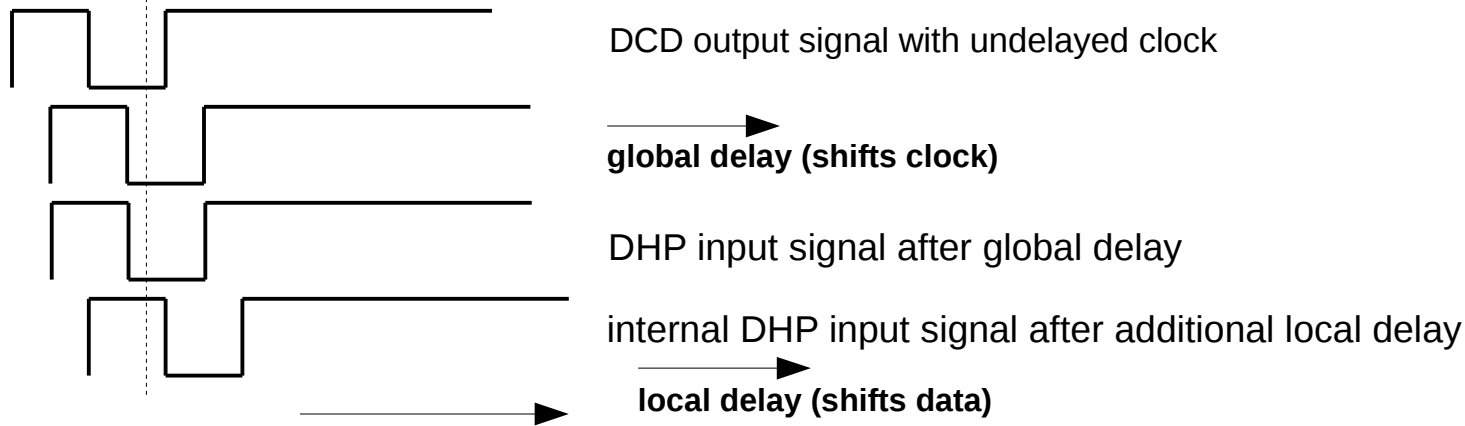
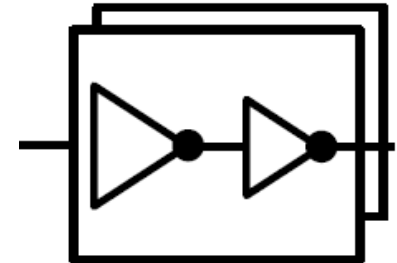
ADC values of zero suppressed data taking dominated by digital errors

- Programmable delay in DHP for every transmission line
- All delay registers 4 bit → 16 settings
- One replica LVDS driver providing reference voltage

Optimization of DCD ↔ DHP communication

- **Delay lines**

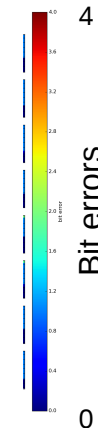
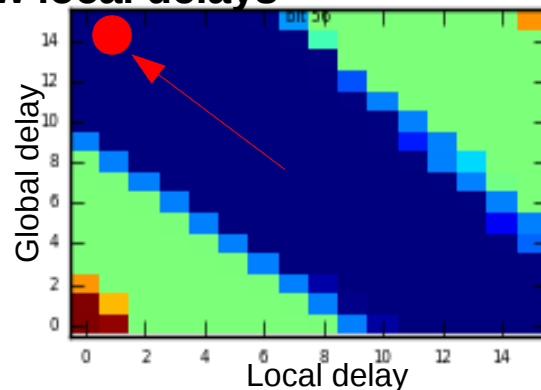
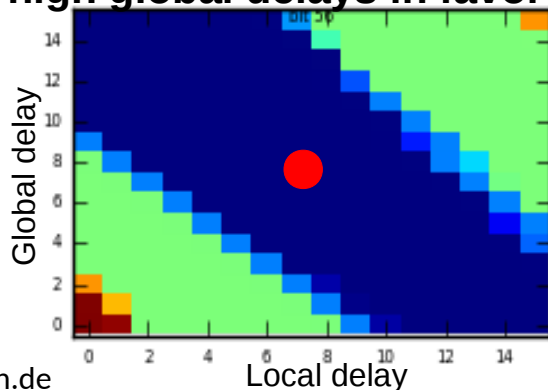
- Known problem in DHPT1.0: asymmetric delays → duty cycle distortion
 - Worse distortion for higher delays
 - **minimize delays for data lines (local delays)**
- Global (clock) and local (data) delays work “in the same direction”:



- → **go to high global delays in favor of low local delays**

● Working point

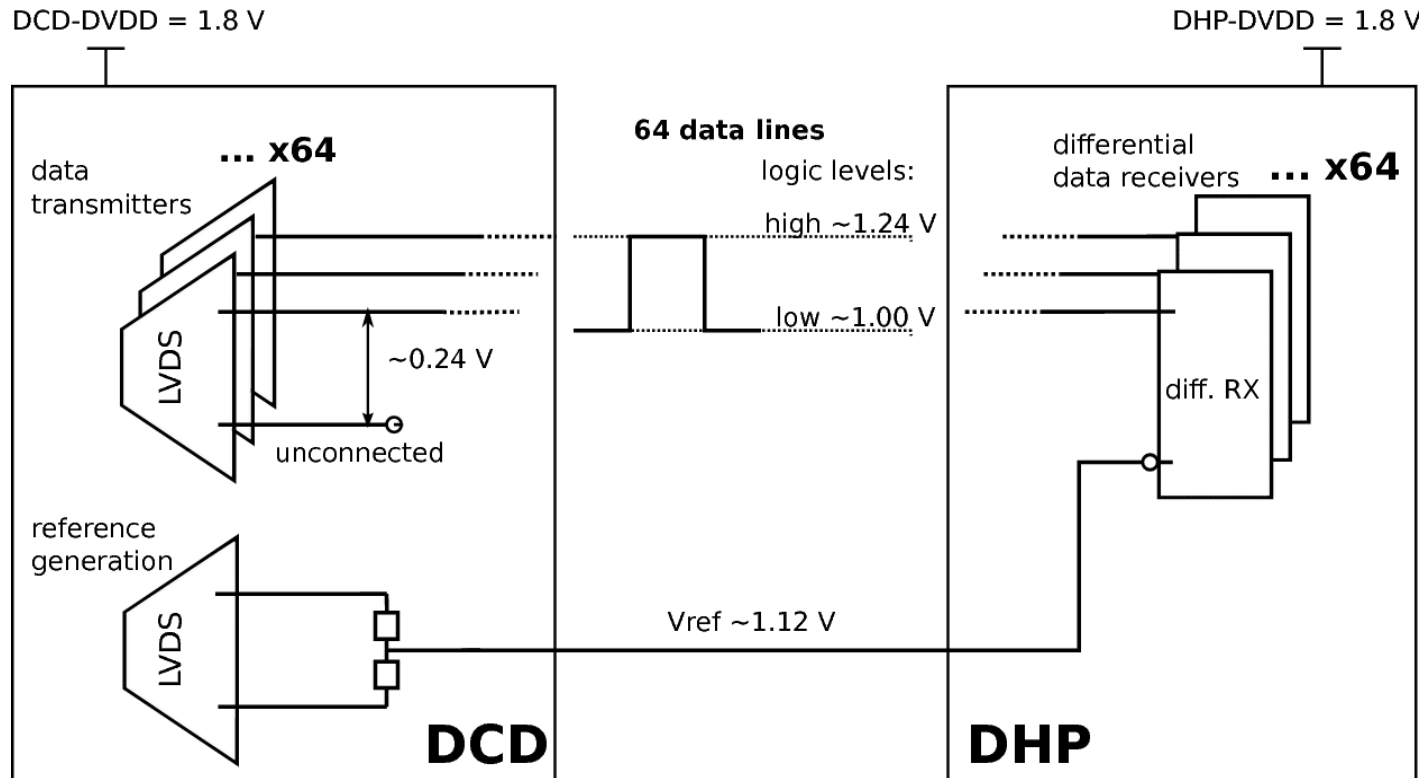
Solution of automatic script: ->



← Better solution for DHPT1.0

For more detail on delay tests see Hybrid 5 talk of Trieste workshop

Optimization of DCD ↔ DHP communication



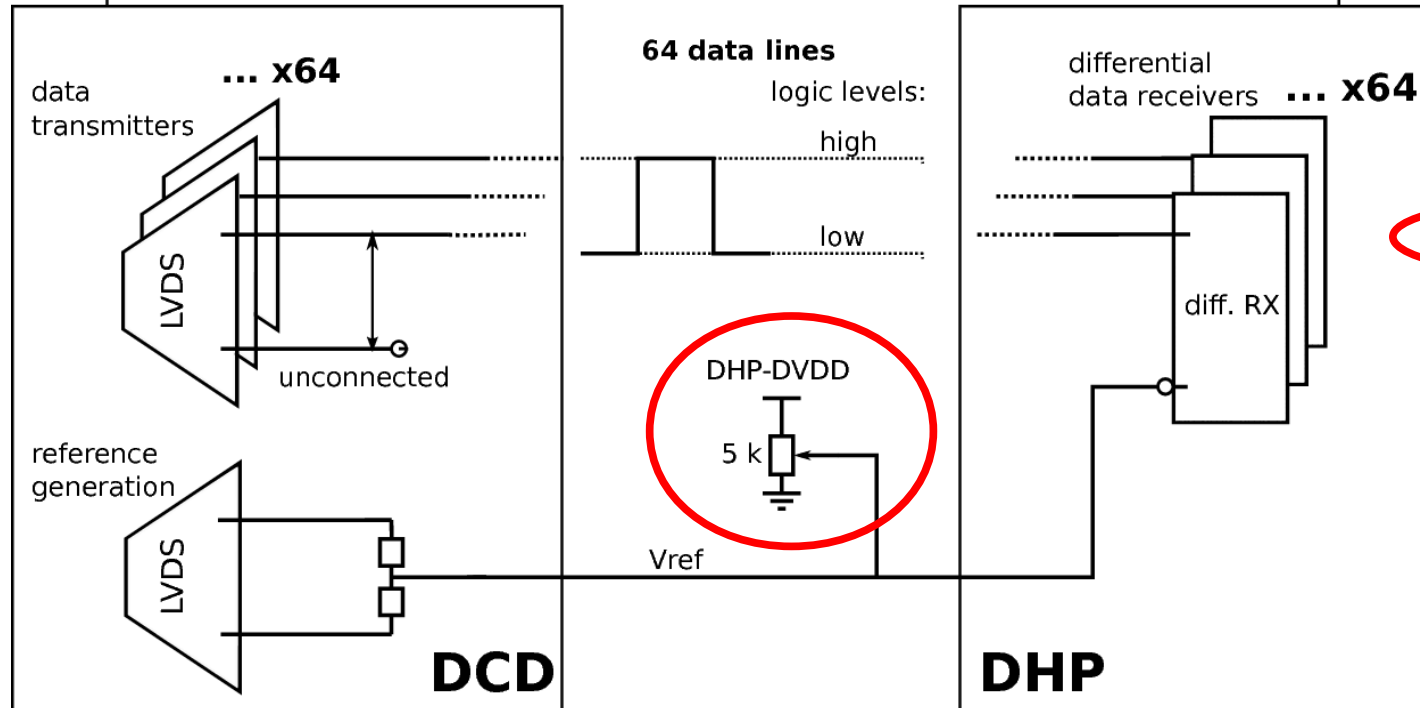
LVDS = Low Voltage Differential Signaling

- LVDS transmitters with one terminal unconnected and one reference for differential receivers
- Possible problems:
 - High/low levels not reached due to long rise/fall times → **use higher supply voltages (DVDD)**
→ **use slower clock** with DHPT1.0
 - Mismatch of Vref w.r.t. logic levels of data lines → **modify Vref** (only Hybrid 5)

Optimization of DCD ↔ DHP communication

DCD-DVDD = 2.1 V

DHP-DVDD = 2.0 V



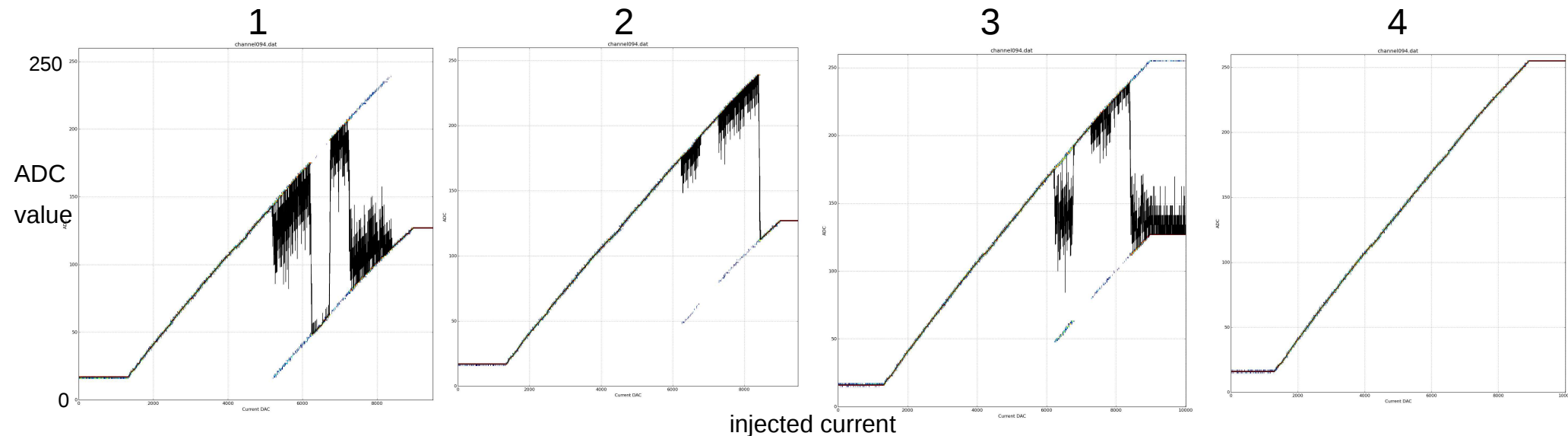
IDAC_DCD_RX_IREF = 255 (max)

LVDS = Low Voltage Differential Signaling

- LVDS transmitters with one terminal unconnected and one reference for differential receivers
- Possible problems:
 - High/low levels not reached due to long rise/fall times → **use higher supply voltages (DVDD)**
→ **use slower clock** with DHPT1.0
 - Mismatch of Vref w.r.t. logic levels of data lines → **modify Vref** (only Hybrid 5)

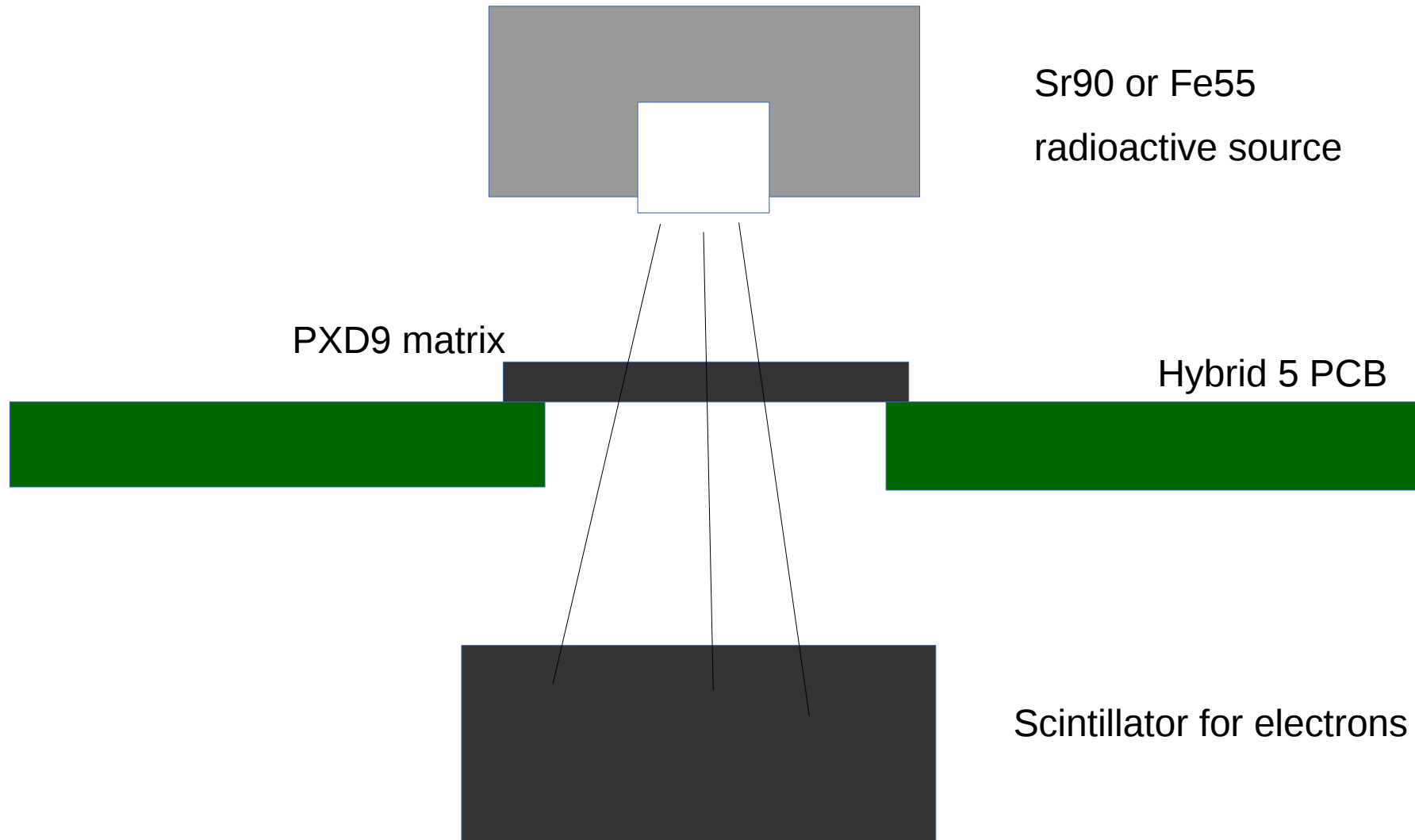
Example of procedure:

- **1:** Initial curve after standard delay optimization
- **2:** Increase digital supply voltages and RX bias current (DCD-DVDD = 2.1 V)
- **3:** Decrease local delay and increase global delay (GD = 14)
- **4:** Increase Vref by 27 mV

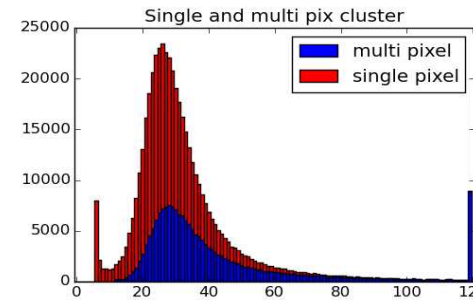
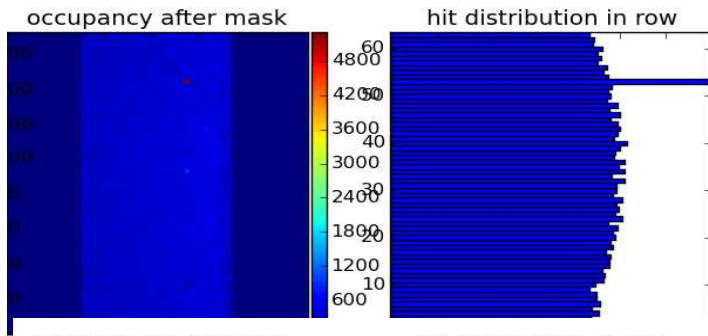


Hybrid 5.0.07 DCD channel 94 with MSB toggling (bit 8 = 127 ADU) @ 62 MHz

- Setup for source measurements:

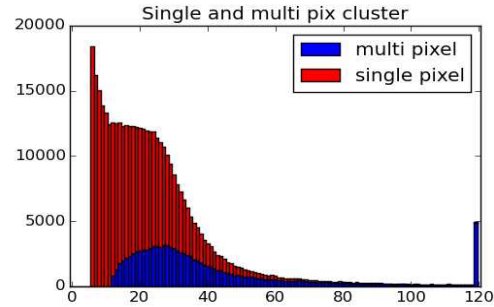
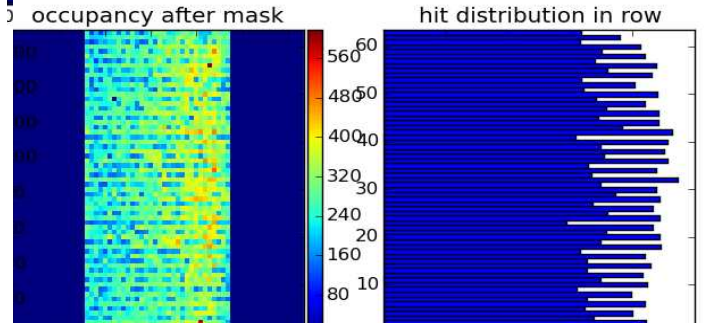


HV: -80 V
Drift: -7 V

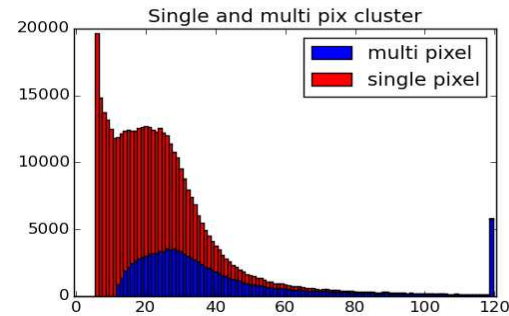
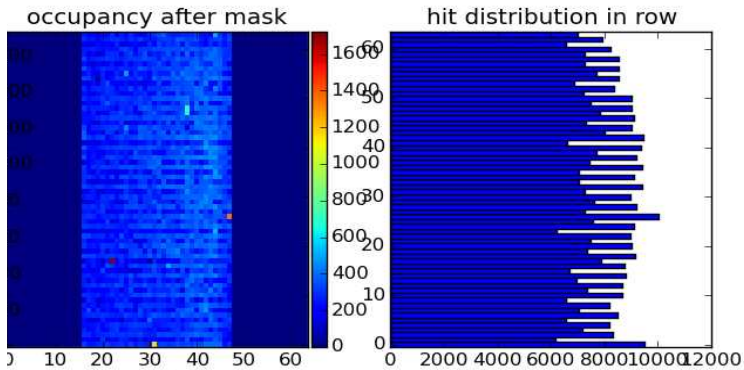


CCG: -1 V
Clear-low: 3 V
Clear-high: 20 V
Gate-on: -2.5 V
Gate-off: 3 V

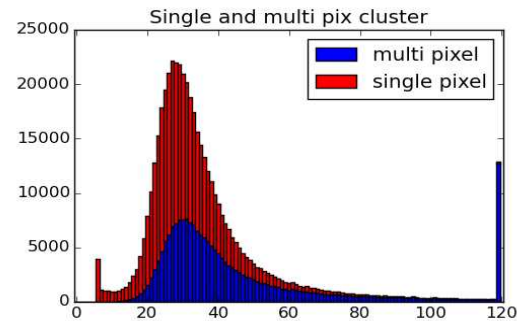
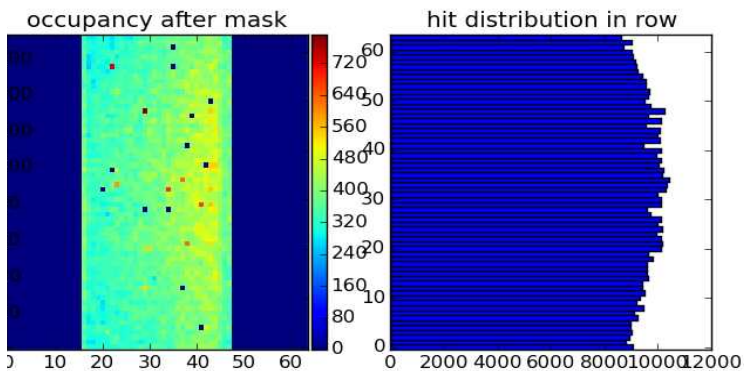
HV: -76 V
Drift: -7 V



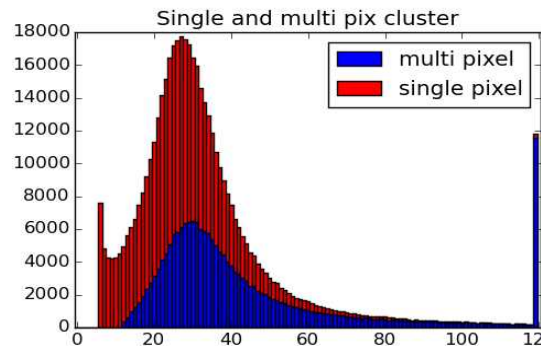
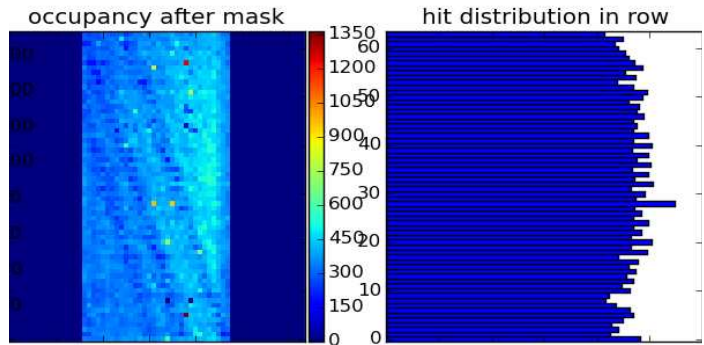
HV: -70 V
Drift: -7 V



HV: -66 V
Drift: -7 V

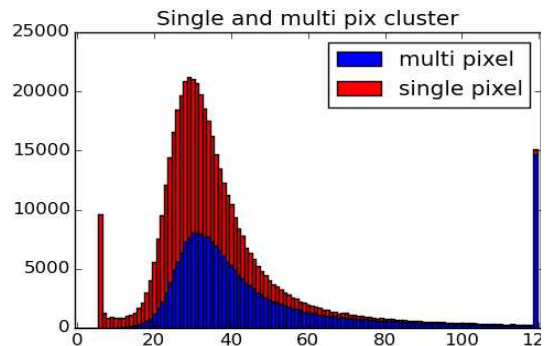
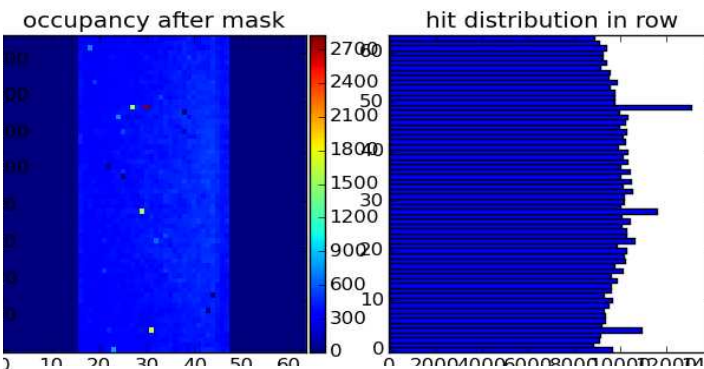


HV: -80 V
Drift: -5 V

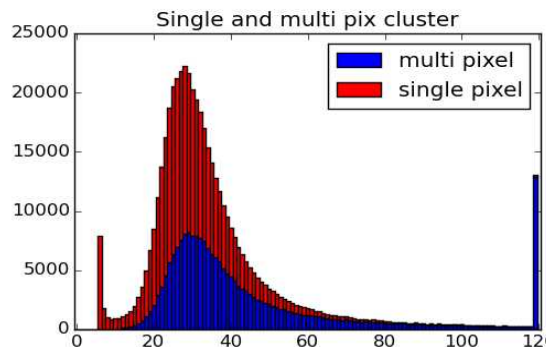
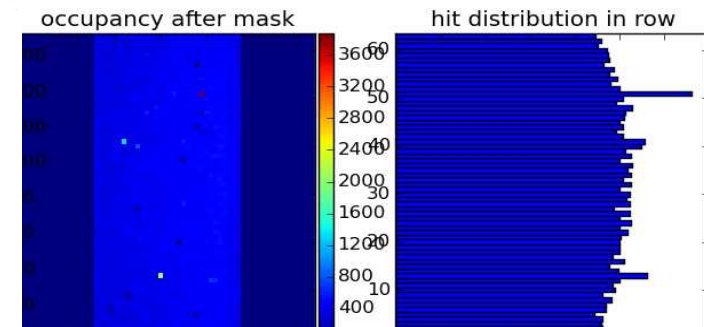


CCG: -1 V
Clear-low: 3 V
Clear-high: 20 V
Gate-on: -2.5 V
Gate-off: 3 V

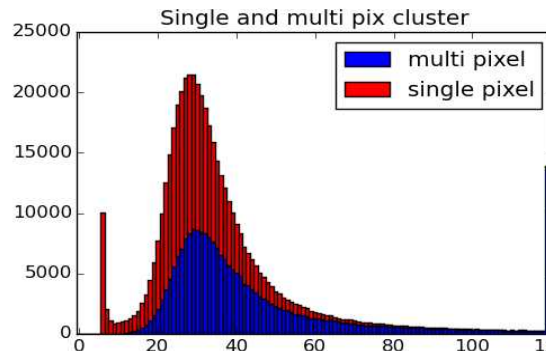
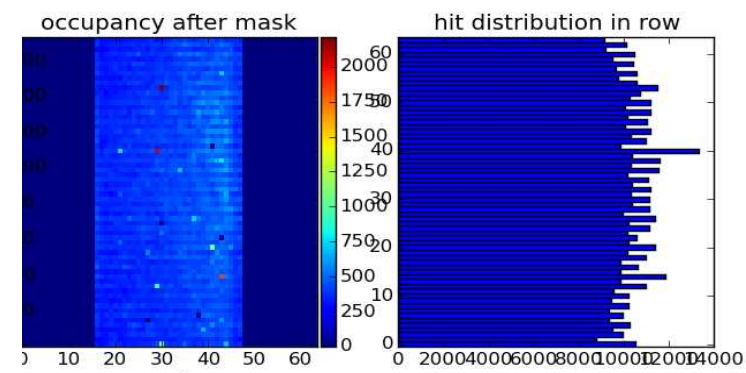
HV: -76 V
Drift: -5 V



HV: -70 V
Drift: -5 V

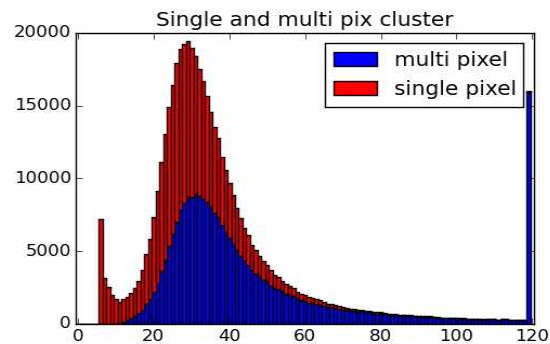
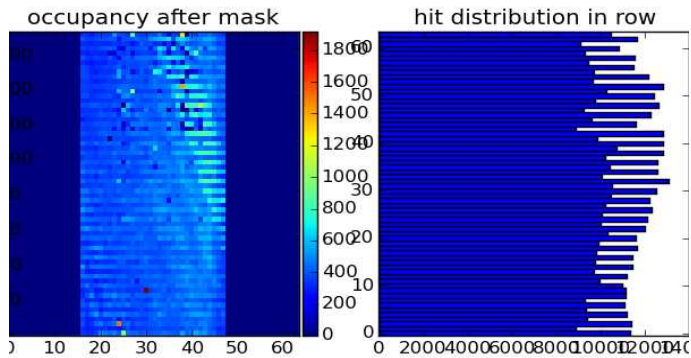


HV: -66 V
Drift: -5 V



HV: -80 V

Drift: -3 V



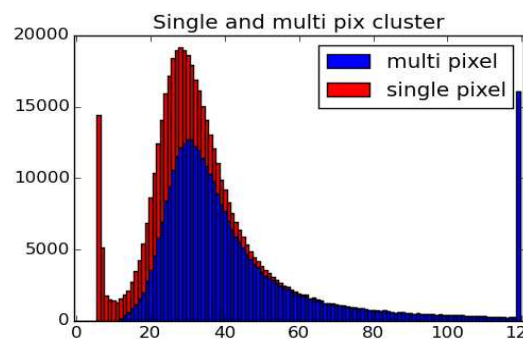
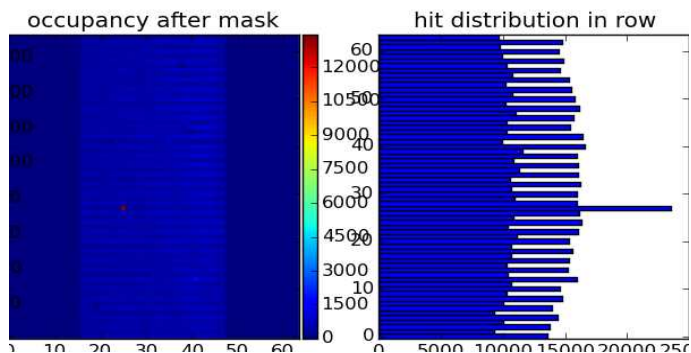
CCG: -1 V

Clear-low: 3 V

Clear-high: 20 V

HV: -76 V

Drift: -3 V

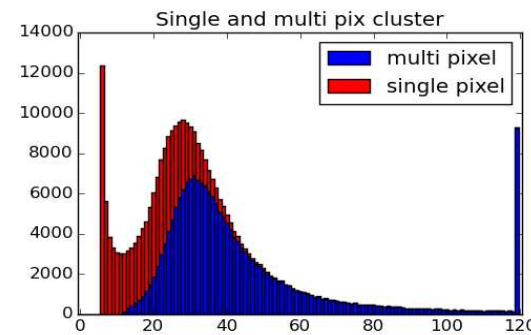
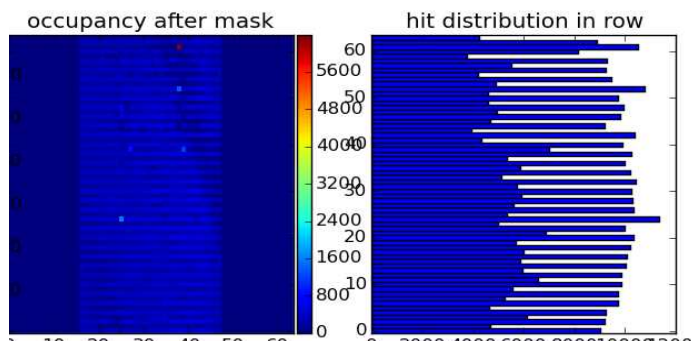


Gate-on: -2.5 V

Gate-off: 3 V

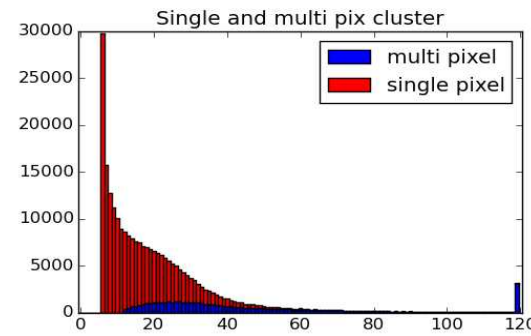
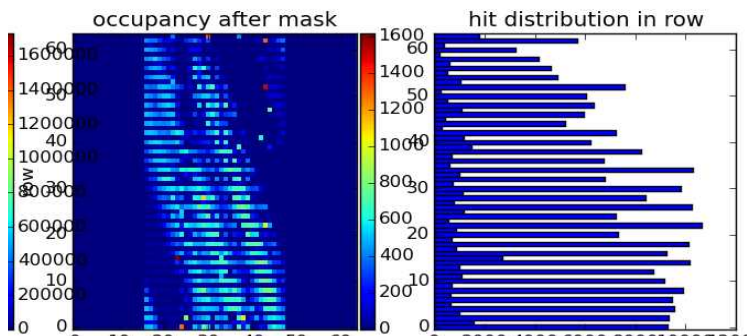
HV: -70 V

Drift: -3 V



HV: -66 V

Drift: -3 V



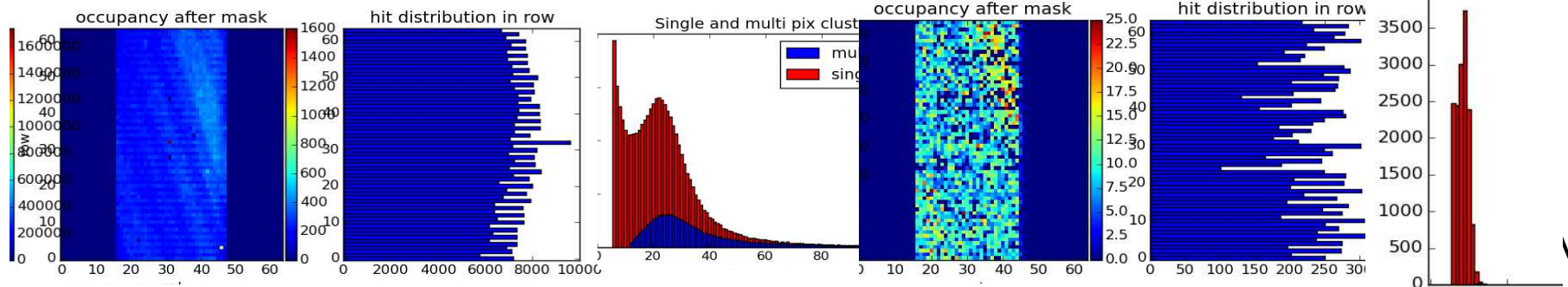
Sr90

Fe55

Singl

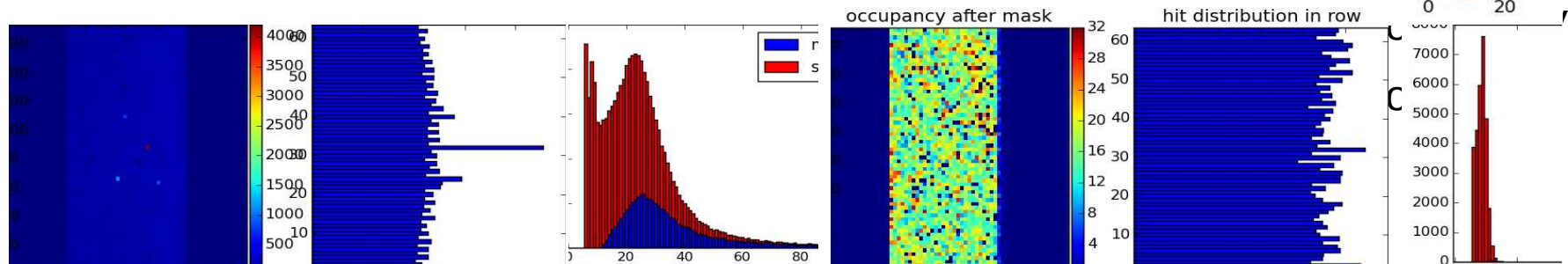
HV: -80 V

Drift: -5 V



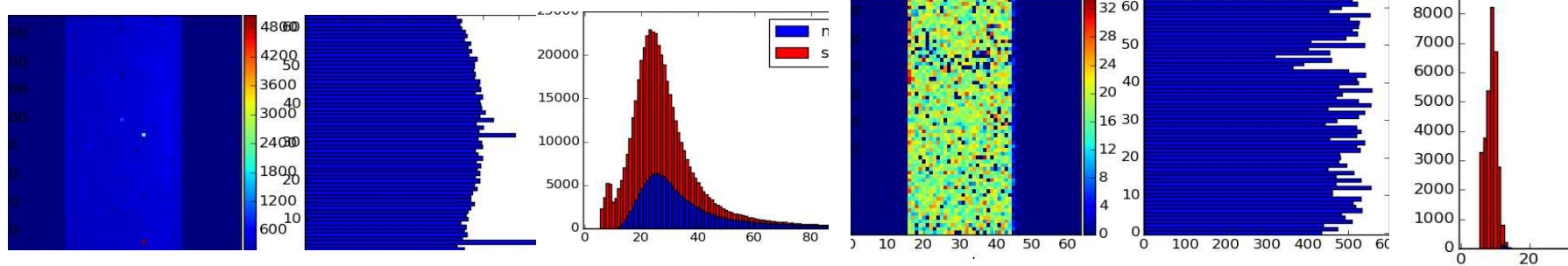
HV: -75 V

Drift: -5 V



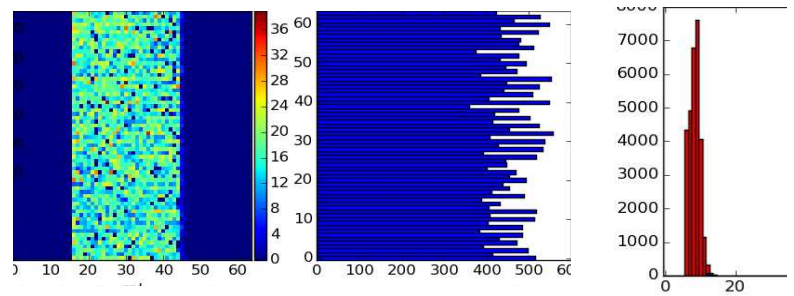
HV: -70 V

Drift: -5 V



HV: -65 V

Drift: -5 V

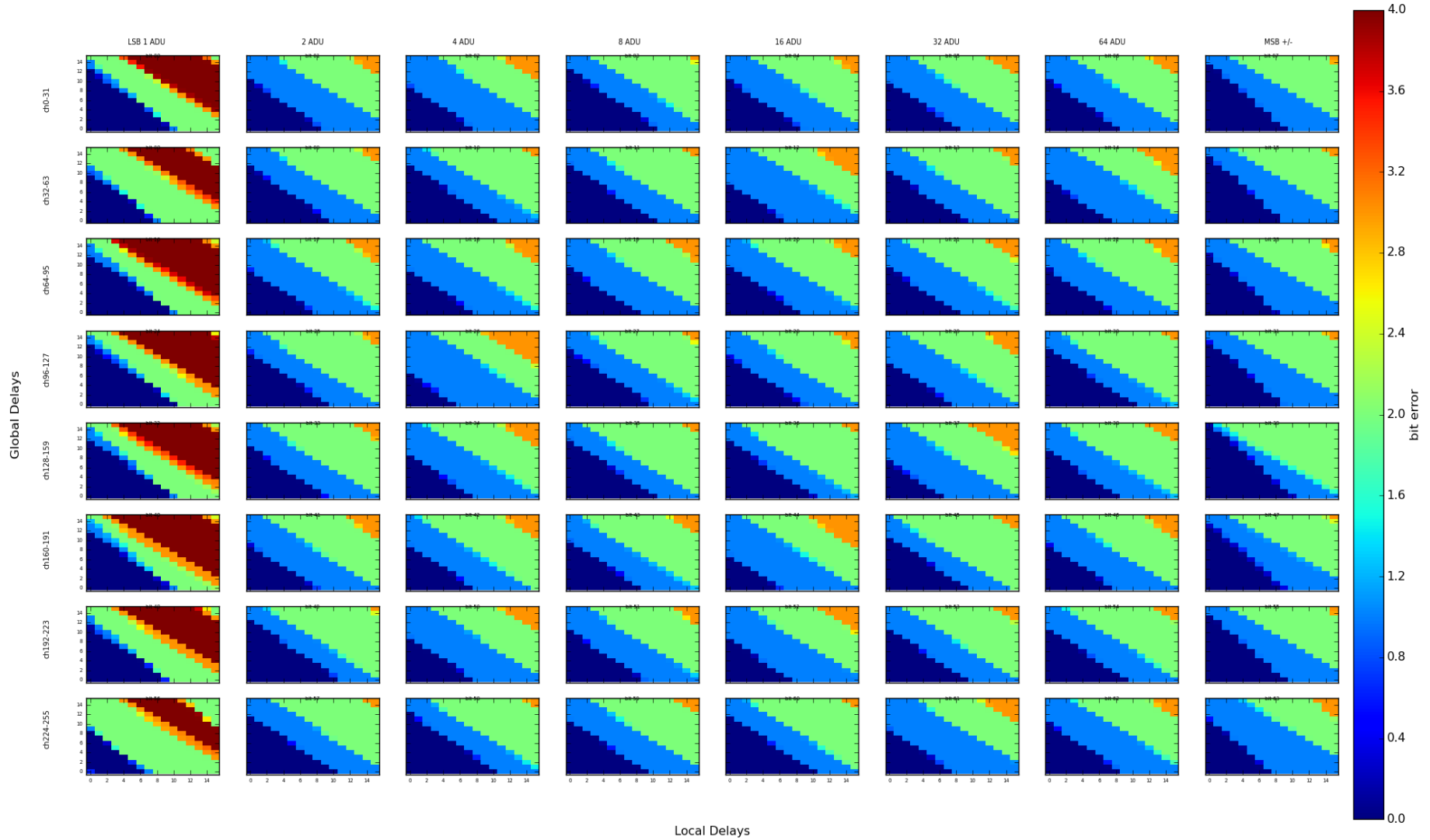


New DHPT1.1 on Hybrid 5

- Two Hybrid 5 assemblies with new DHPT1.1 and DCDpp have been assembled (Hybrid 5.0.08, 5.0.09)
- High speed link to DHH is improved (see Leo's talks)
- DCD ↔ DHP communication should be improved due to lower capacitances

Test Pattern Hybrid 5.0.07 with DHPT1.0 at 76.2 MHz

Delay scan - W18_3 - asicpair: 1

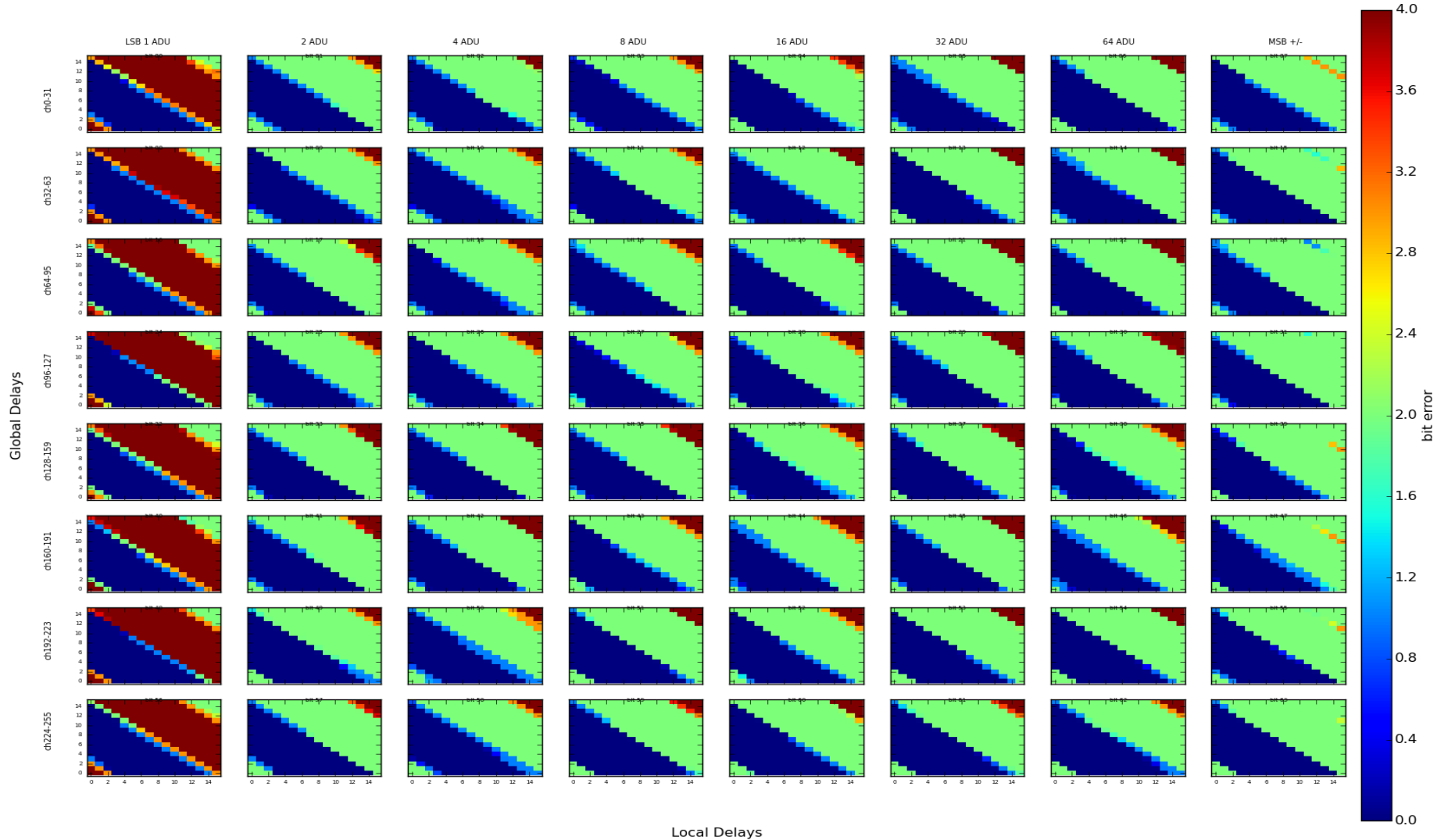


dcd-dvdd = 1900 mV, dhp-core = 1620 mV

asymmetric...

Test Pattern Hybrid 5.0.09 with DHPT1.1 at 76.2 MHz

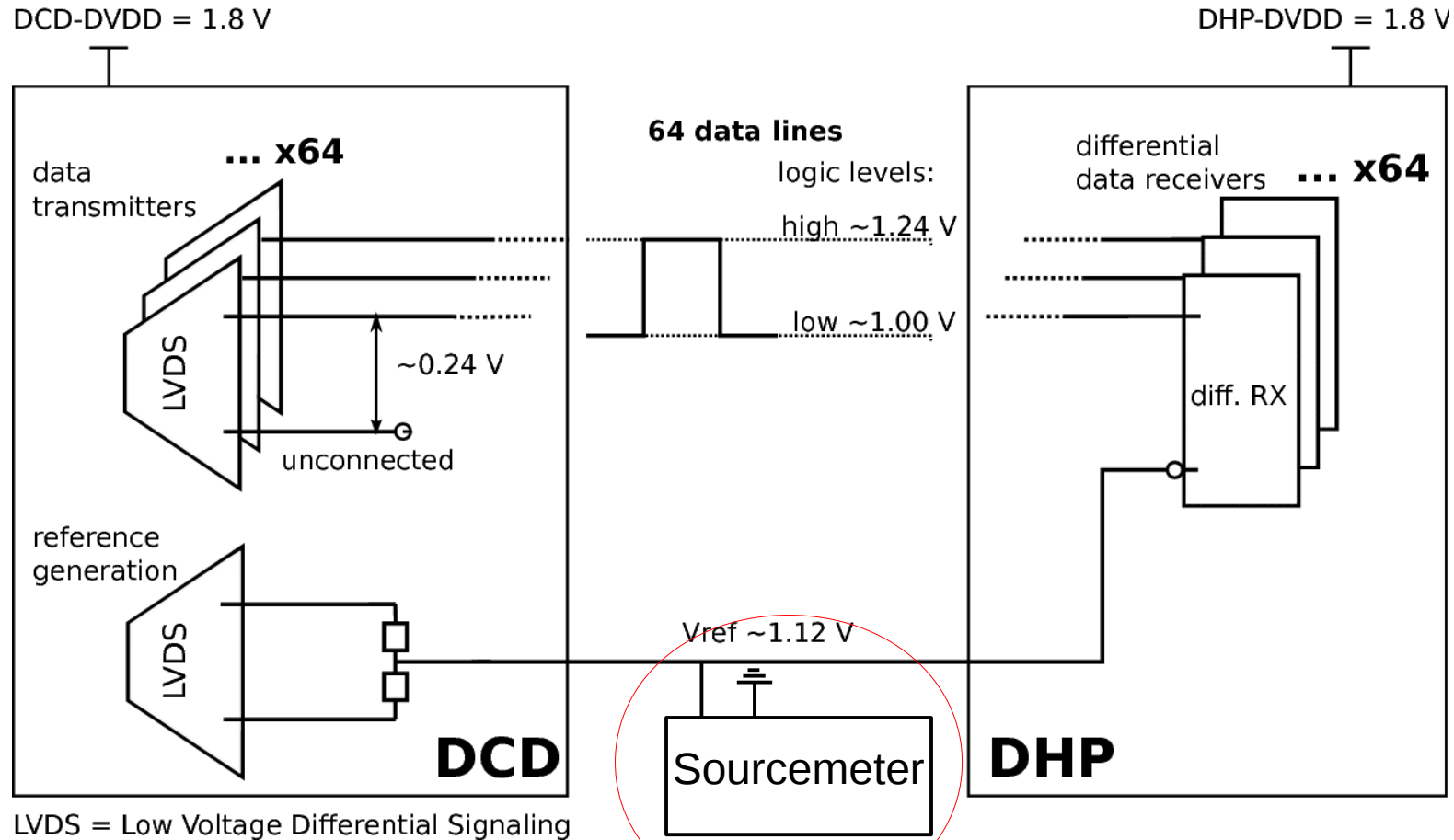
Delay scan - H5_0_09 - asicpair: 1



dcd-dvdd = 1900 mV, dhp-core = 1300 mV

SYMMETRIC!

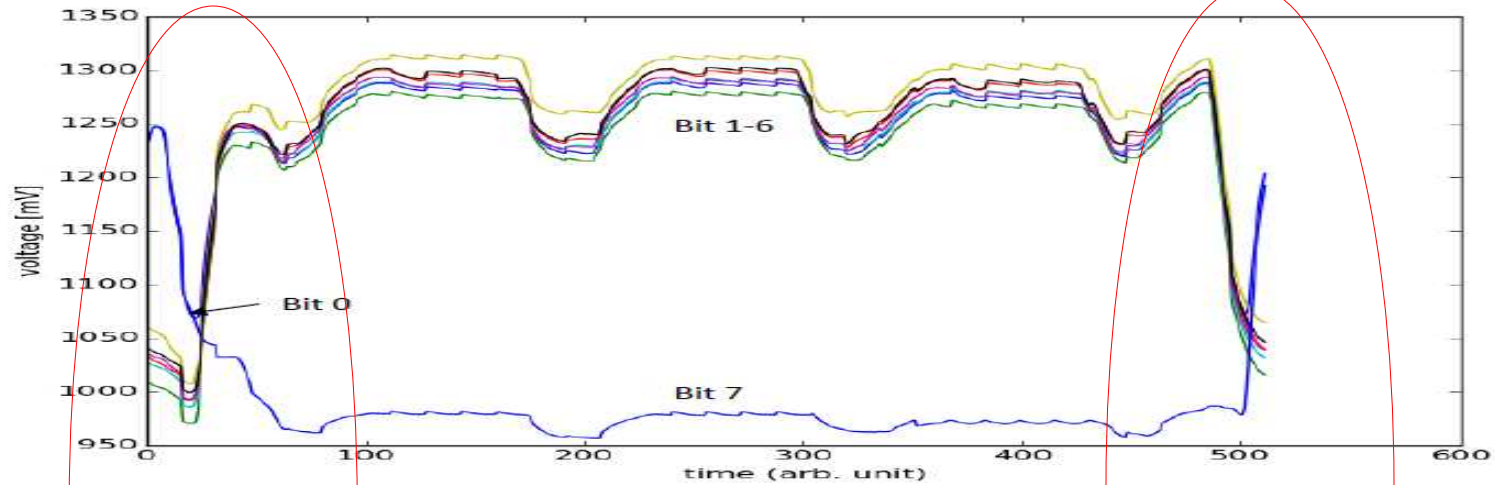
Comparison of Test Pattern with DHPT1.0 and 1.1 with Vref variation



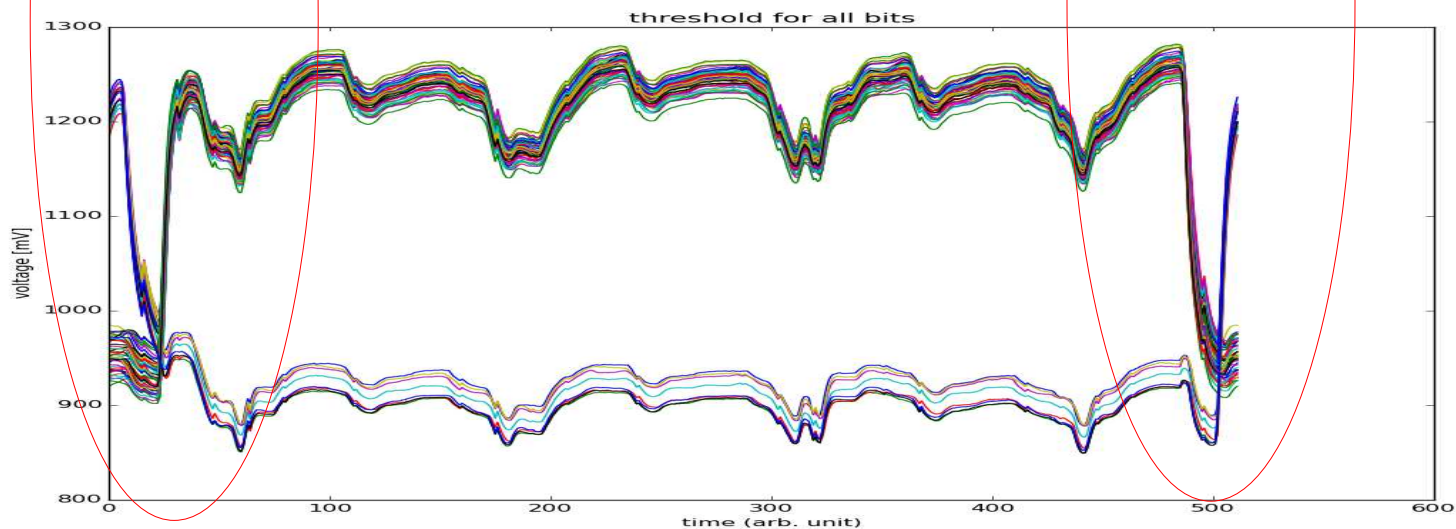
- Overwrite Vref with a sourceme and measure for every point in time of the test pattern for which values the signal flips from 0 to 1 or vice versa
- Emulates sampling oscilloscope when integrating all measurements

Comparison of Test Pattern with DHPT1.0 and 1.1 with V_{ref} variation

DHPT 1.0



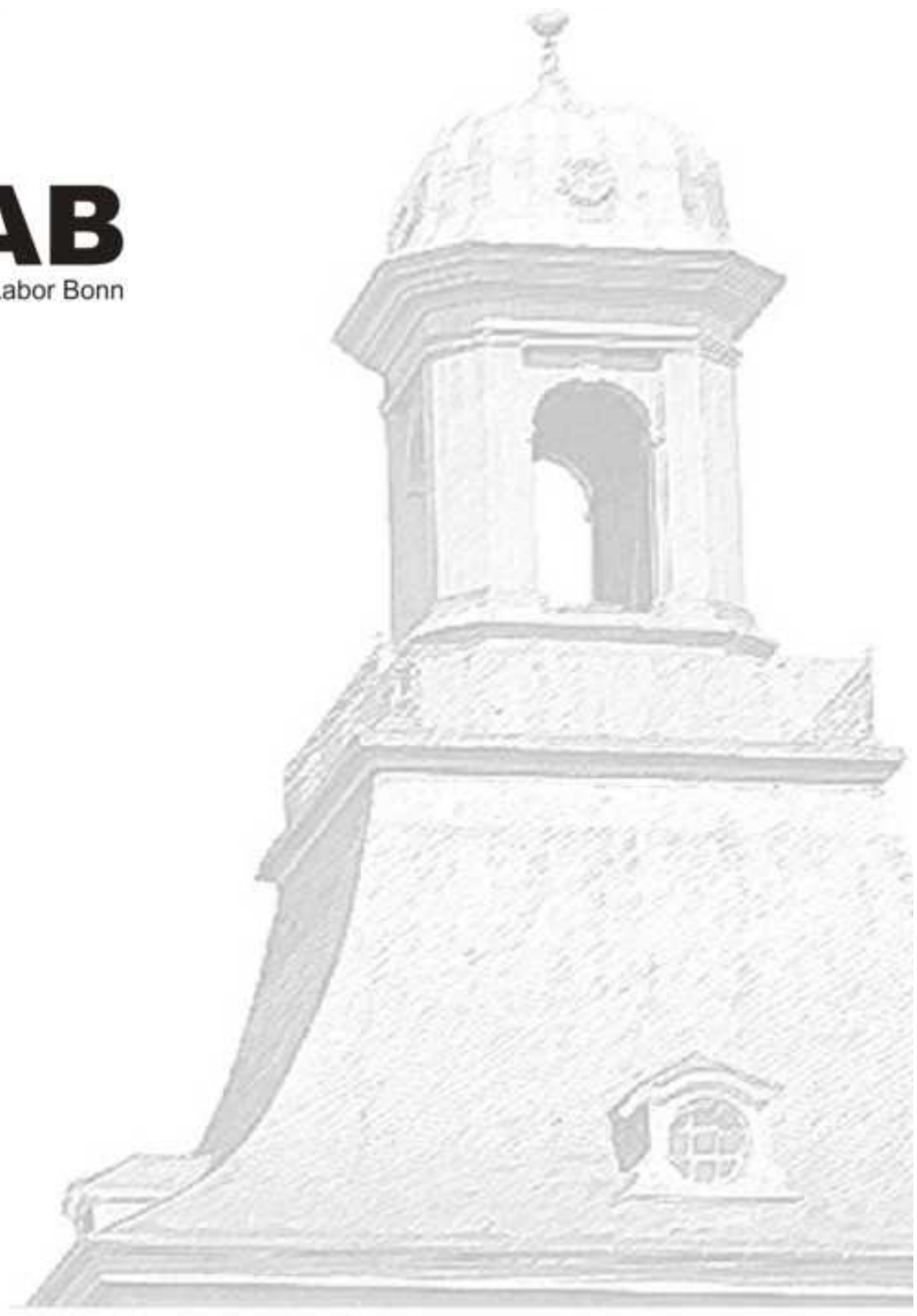
DHPT 1.1



- Edges rise and fall more quickly

- Hybrid 5 with DHPT and DCD is a valuable device for examining the communication between the ASICs
- DHPT1.1 improves the communication already with the unchanged DCDpp
 - Next step:
 - Irradiation campaign in February
- At low clockspeeds (62 MHz instead of 76 MHz) a small PXD9 matrix could successfully be optimized and read out for the first time on a test beam
 - Next steps:
 - Laser scan with sub pixel resolution for detailed charge collection analysis
 - Gated mode investigation with laser setup

Thank you



- half rate DHP ↔ DHE communication
 - DHP doubles all output bits, DHE running at effectively half frequency

